

**Search Notes**

Application/Control No.

10/028,842

Examiner

Isaac M. Woo

Applicant(s)/Patent under  
Reexamination

FRENCH ET AL.

Art Unit

2162

**SEARCHED**

Class	Subclass	Date	Examiner
707	1-10	7/5/2005	IW
707	100-104.1	7/5/2005	IW
707	200-206	7/5/2005	IW
717	168-173	7/5/2005	IW
709	204-207	7/5/5	IW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT, USPG-PUB, EPO, JPO, DERWENT, IBM_TDB), IEEE, ACM	7/5/05	IW